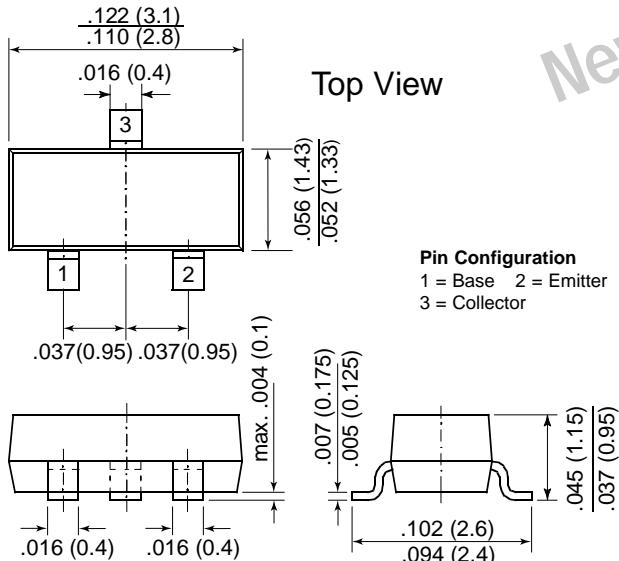


# Small Signal Transistor (PNP)


**TO-236AB (SOT-23)**

*Dimensions in inches and (millimeters)*

## Mechanical Data

**Case:** SOT-23 Plastic Package

**Weight:** approx. 0.008g

**Marking Code:** 2F

**Packaging Codes/Options:**

 E8/10K per 13" reel (8mm tape)  
 E9/3K per 7" reel (8mm tape)

## Features

- PNP Silicon Epitaxial Planar Transistor for switching and amplifier applications.
- This transistor is also available in the TO-92 case with the type designation MPS2907A.

## Maximum Ratings & Thermal Characteristics

*Ratings at 25°C ambient temperature unless otherwise specified.*

Parameters	Symbols	Value	Units
Collector-Emitter Voltage	-V <sub>CEO</sub>	60	V
Collector-Base Voltage	-V <sub>CBO</sub>	60	V
Emitter-Base Voltage	-V <sub>EBO</sub>	5.0	V
Collector Current	-I <sub>C</sub>	600	mA
Power Dissipation <sup>(1)</sup>	P <sub>tot</sub>	225 1.8	mW mW/°C
Power Dissipation <sup>(2)</sup>	P <sub>tot</sub>	300 2.4	mW mW/°C
Thermal Resistance Junction to Ambient Air FR-5 Board Alumina Substrate	R <sub>θJA</sub>	556 417	°C/W
Junction Temperature	T <sub>j</sub>	150	°C
Storage Temperature Range	T <sub>s</sub>	-55 to +150	°C

**Notes:**

(1) FR-5 Board = 1.0 x 0.75 x 0.062 in.

(2) Alumina Substrate = 0.4 x 0.3 x 0.024 in. 99.5% alumina.

**Small Signal Transistor (PNP)**
**Electrical Characteristics** ( $T_J = 25^\circ\text{C}$  unless otherwise noted)

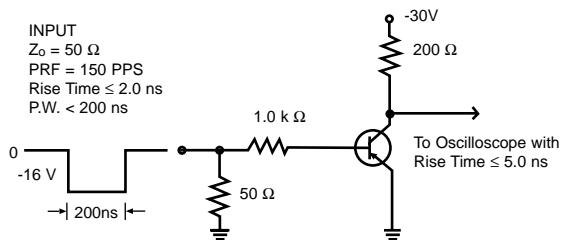
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
DC Current Gain	$h_{FE}$	- $V_{CE} = 10 \text{ V}$ , $-I_C = 0.1 \text{ mA}$	75	—	—	—
		- $V_{CE} = 10 \text{ V}$ , $-I_C = 1 \text{ mA}$	100	—	—	—
		- $V_{CE} = 10 \text{ V}$ , $-I_C = 10 \text{ mA}$	100	—	—	—
		- $V_{CE} = 10 \text{ V}$ , $-I_C = 150 \text{ mA}^{(1)}$	100	—	300	—
		- $V_{CE} = 10 \text{ V}$ , $-I_C = 500 \text{ mA}^{(1)}$	50	—	—	—
Collector Cutoff Current	$-I_{CEX}$	- $V_{EB} = 0.5 \text{ V}$ , $-V_{CE} = 30 \text{ V}$	—	—	50	nA
Collector Cutoff Current	$-I_{CBO}$	- $V_{CB} = 50 \text{ V}$ , $I_E = 0$	—	—	0.01	—
		- $V_{CB} = 50 \text{ V}$ , $I_E = 0, T_A = 125^\circ\text{C}$	—	—	10	$\mu\text{A}$
Emitter-Base Cutoff Current	$-I_{BL}$	- $V_{EB} = 0.5 \text{ V}$ , $-V_{CE} = 30 \text{ V}$	—	—	50	nA
Collector-Emitter Saturation Voltage <sup>(1)</sup>	$-V_{CEsat}$	- $I_C = 150 \text{ mA}$ , $-I_B = 15 \text{ mA}$	—	—	0.4	—
		- $I_C = 500 \text{ mA}$ , $-I_B = 50 \text{ mA}$	—	—	1.6	V
Base-Emitter Saturation Voltage <sup>(1)</sup>	$-V_{BEsat}$	- $I_C = 150 \text{ mA}$ , $-I_B = 15 \text{ mA}$	—	—	1.3	—
		- $I_C = 500 \text{ mA}$ , $-I_B = 50 \text{ mA}$	—	—	2.6	V
Collector-Emitter Breakdown Voltage <sup>(1)</sup>	$-V_{(BR)CEO}$	- $I_C = 10 \text{ mA}$ , $I_B = 0$	60	—	—	V
Collector-Base Breakdown Voltage	$-V_{(BR)CBO}$	- $I_C = 10 \mu\text{A}$ , $I_E = 0$	60	—	—	V
Emitter-Base Breakdown Voltage	$-V_{(BR)EBO}$	- $I_E = 10 \mu\text{A}$ , $I_C = 0$	5.0	—	—	V
Current Gain-Bandwidth Product	$f_T$	- $V_{CE} = 20 \text{ V}$ , $-I_C = 50 \text{ mA}$ $f = 100 \text{ MHz}$	200	—	—	MHz
Output Capacitance	$C_{obo}$	- $V_{CB} = 10 \text{ V}$ , $f = 1.0 \text{ MHz}$ $I_E = 0$	—	—	8	pF
Input Capacitance	$C_{ibo}$	- $V_{EB} = 2.0 \text{ V}$ , $f = 1.0 \text{ MHz}$ $I_C = 0$	—	—	30	pF

**Notes:**

(1) Pulse test: Pulse width  $\leq 300 \mu\text{s}$ , duty cycle  $\leq 2.0\%$

**Small Signal Transistor (PNP)**
**Electrical Characteristics** ( $T_J = 25^\circ\text{C}$  unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Turn-ON Time	$t_{on}$	$-I_{B1} = 15 \text{ mA}, -I_C = 150 \text{ mA}$ $-V_{CC} = 30 \text{ V}$	—	—	45	ns
Delay Time	$t_d$	$-I_{B1} = 15 \text{ mA}, -I_C = 150 \text{ mA}$ $-V_{CC} = 30 \text{ V}$	—	—	10	ns
Rise Time	$t_r$	$-I_{B1} = 15 \text{ mA}, -I_C = 150 \text{ mA}$ , $-V_{CC} = 30 \text{ V}$	—	—	40	ns
Turn-OFF Time	$t_{off}$	$-I_{B1} = 15 \text{ mA}, -I_C = 150 \text{ mA}$ $-V_{CC} = 6.0 \text{ V}$	—	—	100	ns
Storage Time	$t_s$	$-I_{B1} = -I_{B2} = 15 \text{ mA}$ , $-I_C = 150 \text{ mA}$ , $-V_{CC} = 6.0 \text{ V}$	—	—	80	ns
Fall Time	$t_f$	$-I_{B1} = -I_{B2} = 15 \text{ mA}$ , $-I_C = 150 \text{ mA}$ , $-V_{CC} = 6 \text{ V}$	—	—	30	ns

**Switching Time Equivalent Test Circuit**
**Figure 1 - Delay and Rise Time Test Circuit**

**Figure 2 - Storage and Fall Time Test Circuit**
